

L Number	Hits	Search Text	DB	Time stamp
1	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	IBM_TDB	2004/05/13 15:08
2	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	US-PGPUB	2004/05/13 15:22
3	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	EPO	2004/05/13 15:06
4	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	JPO	2004/05/13 15:07
5	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	DERWENT	2004/05/13 15:07
6	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	USOCR	2004/05/13 15:07
7	0	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	USPAT	2004/05/13 15:07
8	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	IBM_TDB	2004/05/13 15:10
9	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	US-PGPUB	2004/05/13 15:09
10	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	EPO	2004/05/13 15:09

11	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	JPO	2004/05/13 15:09
12	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	DERWENT	2004/05/13 15:09
13	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	USOCR	2004/05/13 15:09
14	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	USPAT	2004/05/13 15:09
15	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	IBM_TDB	2004/05/13 15:10
16	103	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	US-PGPUB	2004/05/13 15:13
17	1	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) same ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	US-PGPUB	2004/05/13 15:13
18	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) same ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	EPO	2004/05/13 15:13
19	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	EPO	2004/05/13 15:13
20	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	JPO	2004/05/13 15:13
21	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	DERWENT	2004/05/13 15:14
22	13	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	USOCR	2004/05/13 15:22
23	91	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	USPAT	2004/05/13 16:15
24	17	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	US-PGPUB	2004/05/13 15:59

25	16	(mems! or (micro adj (electromechanical or electromechanically)) or microelectromechanical or microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling)))	USPAT	2004/05/13 15:59
26	0	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) same ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or channelling))	USPAT	2004/05/13 16:16
27	3	(jp-07105580-\$ or jp-61133065-\$ or jp-01264403-\$).did.	DERWENT	2004/05/13 16:20
28	1	jp-01262403-\$.did.	DERWENT	2004/05/13 16:21

DERWENT-ACC-NO: 1995-188360

DERWENT-WEEK: 199525

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TITLE: Non-volatile
information recording medium - includes
layer of silver@,
indium@, antimony@ and tellurium@
heated for recording
by creating difference from one
point to another using
scanning type tunnel microscope
probe generating
tunnel current

PATENT-ASSIGNEE: HITACHI LTD[HITA]

PRIORITY-DATA: 1993JP-0250300 (October 6,
1993)

PATENT-FAMILY:

PUB-NO	LANGUAGE	PUB-DATE	PAGES	MAIN-IPC
JP 07105580 A		April 21, 1995		
N/A		004		G11B 009/04

APPLICATION-DATA:

PUB-NO	APPL-DESCRIPTOR
APPL-NO	APPL-DATE
JP 07105580A	N/A

1993JP-0250300

October 6, 1993

INT-CL (IPC): G11B009/04, H01F010/08

ABSTRACTED-PUB-NO: JP 07105580A

BASIC-ABSTRACT:

The recording type layer (3) is mounted on an electrode layer (2) formed from a high fusing point material. This electrode layer is, in turn, mounted on a conductive substrate (1).

A scanning type tunnel microscope probe carries out heating of the recording type layer to create a difference from one point to another by passing current through it. Based on the electrical conductivity of the element constituting the layer, a tunnel current flows between this layer and the electrode layer. Thus, multiple information is recorded by this process on the recording type layer.

ADVANTAGE - Enables recording of large scale information. Provides recording path of several 10 nm for single bit of data.

CHOSEN-DRAWING: Dwg.1/2

DERWENT-CLASS: T03

EPI-CODES: T03-C05; T03-C09;

DERWENT-ACC-NO: 1989-351865

DERWENT-WEEK: 198948

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TITLE: Probe for inner
atomic force microscope - has flexible
silicon oxide-silicon
nitride plates, and provides plate
top end with needle
chip NoAbstract Dwg 2/4

PATENT-ASSIGNEE: HITACHI LTD[HITA]

PRIORITY-DATA: 1988JP-0089024 (April 13,
1988)

PATENT-FAMILY:

PUB-NO	LANGUAGE	PUB-DATE	PAGES	MAIN-IPC
JP 01262403 A		October 19, 1989		
N/A			004	N/A

APPLICATION-DATA:

PUB-NO	APPL-DESCRIPTOR
APPL-NO	APPL-DATE
JP 01262403A	N/A
1988JP-0089024	April 13, 1988

INT-CL (IPC): G01B007/34, G01N023/00 ,
H01J037/08

ABSTRACTED-PUB-NO:

EQUIVALENT-ABSTRACTS:

DERWENT-CLASS: S02 S03 V05

EPI-CODES: S02-A02X; S03-E02X; S03-E06B;
V05-F01; V05-F03;